

LISTING OF THE PENDING CLAIMS

1. (original) A method of adjusting characteristics of an electronic part, comprising:
 - (a) measuring at least one characteristic of said electronic part;
 - (b) performing an electromagnetic field simulation to determine a value of said characteristic which is to be obtained when the value of at least one structural parameter of said electronic part is varied from a design value; and
 - (c) adjusting said structural parameter based on step (b).

2. (original) A method of adjusting characteristics of an electronic part, comprising:
 - (a) measuring at least one characteristic of said electronic part;
 - (b) performing an electromagnetic field simulation to determine a value of said characteristic which is to be obtained when the value of at least one of a plurality of structural parameters of said electronic part is varied from a design value, said plurality of structural parameters being dimensions of a plurality of pre-selected portions of said electronic part;
 - (c) determining the amount of variation of the value of the structural parameter from the design value which has to be effected to make the measured value of said characteristic fall within a predetermined range of allowable error from the design value; and
 - (d) adjusting the value of said structural parameter by an amount corresponding to said amount of variation.

3. (original) A method of adjusting characteristics of an electronic part according to claim 2, further comprising the steps of:

determining, from the results of said electromagnetic field simulation, correlations between the amounts of variations of the value of the structural parameter and the amounts of deviations of the value of said characteristics from the design value; and storing the correlations in the form of table data;

wherein the amount of variation of the value of the structural parameter, determined in step (c) and corresponding to the amount of deviation of the measured value of said item of the characteristics from the design characteristic value, is derived from said table data.

4. (original) A method of adjusting characteristics of an electronic part according to claim 3, wherein steps (a)-(c) are cyclically repeated while setting the amount of adjustment in step (d) in each cycle to a value smaller than said amount of variation, thereby bringing the value of said characteristic closer to the design value.